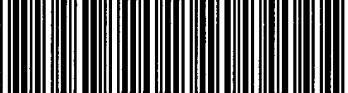


<b>Search Notes</b> 				<b>Application/Control No.</b> 10/721,512 <b>Examiner</b> Hai V. Nguyen	<b>Applicant(s)/Patent under Reexamination</b> KOBAYASHI ET AL.	
<b>SEARCHED</b>				<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>		
Class	Subclass	Date	Examiner	DATE	EXMR	
358	1.14	9/26/2006	HN	9/26/2006	HN	
358	1.15					
<b>INTERFERENCE SEARCHED</b>						
Class	Subclass	Date	Examiner			